

N-CHANNEL SILICON POWER MOS-FET

FAP-III A SERIES

Features

- High current
- Low on-resistance
- No secondary breakdown
- Low driving power
- High forward Transconductance
- Avalanche-proof
- Including G-S Zenner diode

Applications

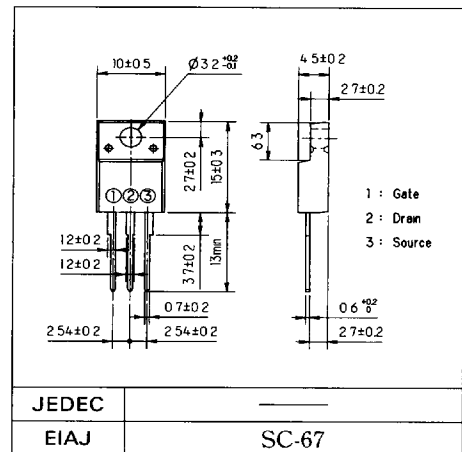
- Motor controllers
- General purpose power amplifier
- DC-DC converters

Max. Ratings and Characteristics

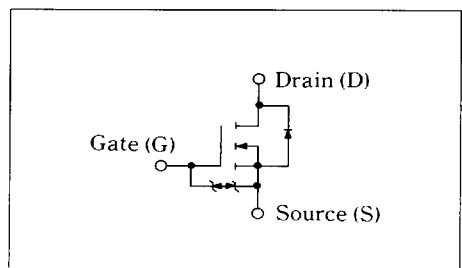
- Absolute Maximum Ratings($T_c = 25^\circ\text{C}$)
(unless otherwise specified)

Items	Symbols	Ratings	Units
Drain-source voltage	V_{DS}	60	V
Drain-gate voltage($R_{GS} = 20K\Omega$)	V_{DGR}	60	V
Continuous drain current	I_D	40	A
Pulsed drain current	$I_{D(PULS)}$	160	A
Gate-source voltage	V_{GS}	± 20	V
Max. power dissipation	P_D	40	W
Operating and storage temperature range	T_{ch} T_{slg}	150 $-55 \sim +150$	$^\circ\text{C}$ $^\circ\text{C}$

Outline Drawings



Equivalent Circuit Schematic



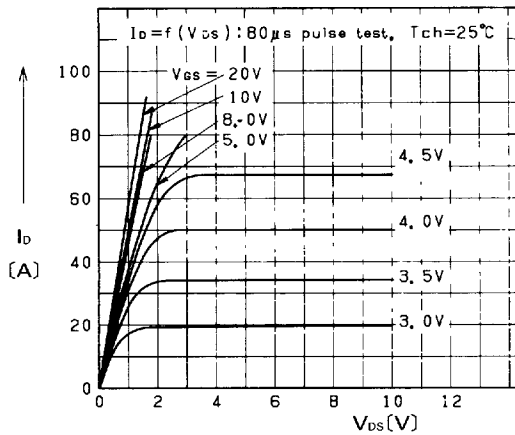
- Electrical Characteristics($T_c = 25^\circ\text{C}$) (unless otherwise specified)

Items	Symbols	Test Conditions	Min.	Typ.	Max.	Units
Drain-source breakdown voltage	$V_{(BR)DSS}$	$I_D = 1\text{mA}$ $V_{GS} = 0\text{V}$	60			V
Gate threshold voltage	$V_{GS(th)}$	$I_D = 1\text{mA}$ $V_{DS} = V_{GS}$	1.0	1.5	2.0	V
Zero gate voltage drain current	I_{DSS}	$V_{DS} = 60\text{V}$ $V_{GS} = 0\text{V}$ $T_{ch} = 25^\circ\text{C}$			500	μA
		$T_{ch} = 125^\circ\text{C}$			1.0	mA
Gate-source leakage current	I_{GSS}	$V_{GS} = \pm 16\text{V}$ $V_{DS} = 0\text{V}$			10.0	μA
Drain-source on-state resistance	$R_{DS(on)}$	$I_D = 20\text{A}$ $V_{GS} = 4\text{V}$		30.0	50.0	m Ω
		$V_{GS} = 10\text{V}$		20.0	30.0	m Ω
Forward transconductance	g_{fs}	$I_D = 20\text{A}$ $V_{DS} = 25\text{V}$	13.0	25.0		S
Input capacitance	C_{iss}	$V_{DS} = 25\text{V}$		1600	2400	pF
Output capacitance	C_{oss}	$V_{GS} = 0\text{V}$		580	870	
Reverse transfer capacitance	C_{rss}	$f = 1\text{MHz}$		320	480	ns
Turn-on time t_{on} ($t_{on} = t_{d(on)} + t_r$)	$t_{d(on)}$	$V_{CC} = 30\text{V}$ $I_D = 40\text{A}$ $V_{GS} = 10\text{V}$ $R_{GS} = 25\Omega$		15	23	
	t_r			90	140	
Turn-off time t_{off} ($t_{off} = t_{d(off)} + t_f$)	$t_{d(off)}$			300	450	
	t_f			190	290	
Avalanche capability	I_{AV}	$L = 100\mu\text{H}$ $T_{ch} = 25^\circ\text{C}$	40.0			A
Continuous reverse drain current	I_{DR}	$T_c = 25^\circ\text{C}$			40.0	A
Pulsed reverse drain current	I_{DRM}	$T_c = 25^\circ\text{C}$			160.0	A
Diode forward on-voltage	V_{SD}	$I_F = 2 \times I_{DR}$ $V_{GS} = 0\text{V}$ $T_{ch} = 25^\circ\text{C}$		1.40		V
Reverse recovery time	t_{rr}	$I_F = I_{DR}$ $V_{GS} = 0\text{V}$		80.0		ns
Reverse recovery charge	Q_{rr}	$-dI_F/dt = 100\text{A}/\mu\text{s}$ $T_{ch} = 25^\circ\text{C}$		0.17		μC

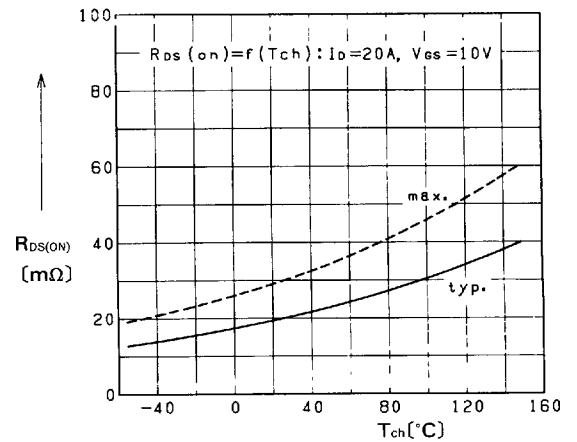
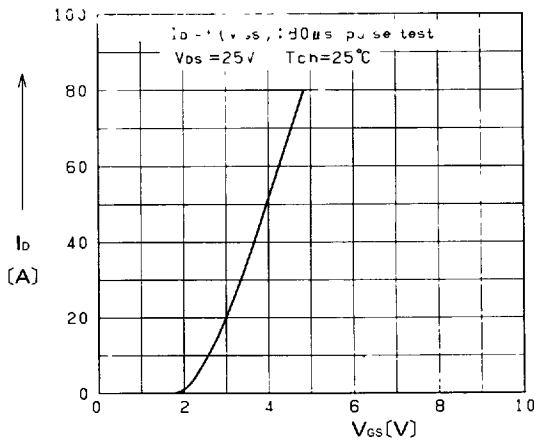
Thermal Characteristics

Items	Symbols	Test Conditions	Min.	Typ.	Max.	Units
Thermal resistance	$R_{th(ch-a)}$	channel to air			62.5	$^\circ\text{C}/\text{W}$
	$R_{th(ch-c)}$	channel to case			3.125	$^\circ\text{C}/\text{W}$

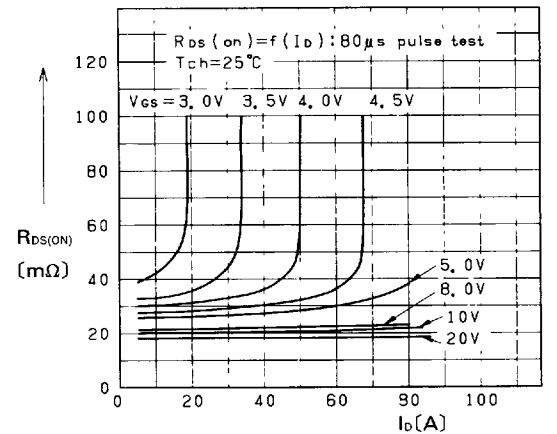
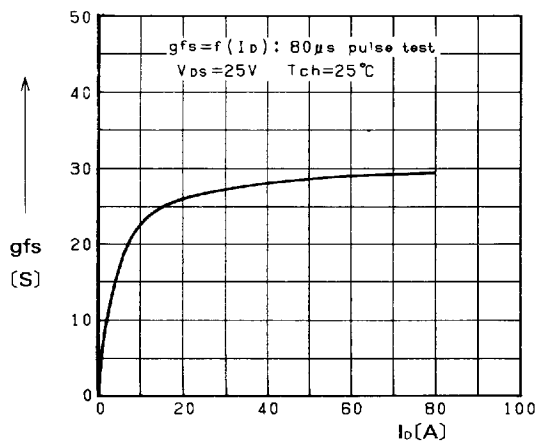
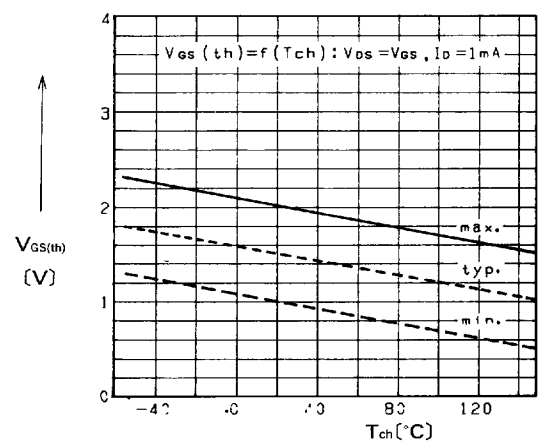
Characteristics

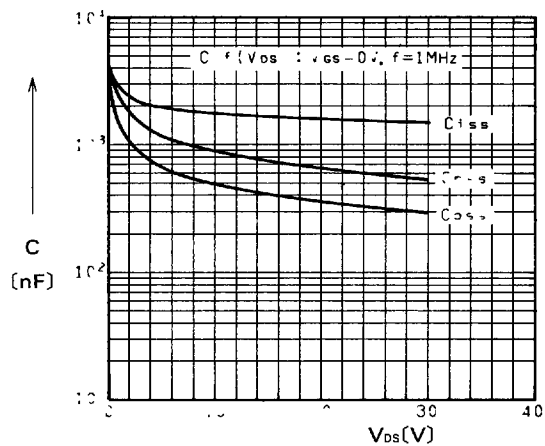
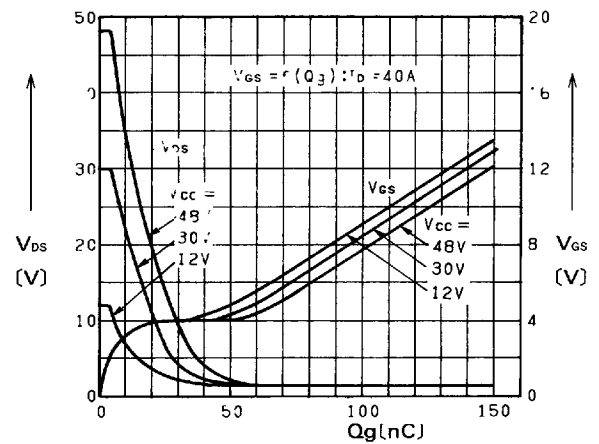


Typical Output Characteristics

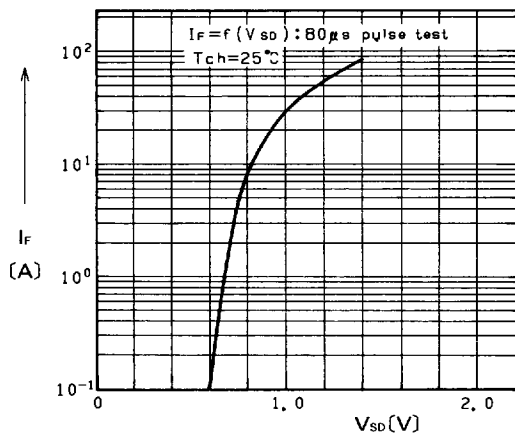
On-State Resistance vs. T_{ch} 

Typical Transfer Characteristics

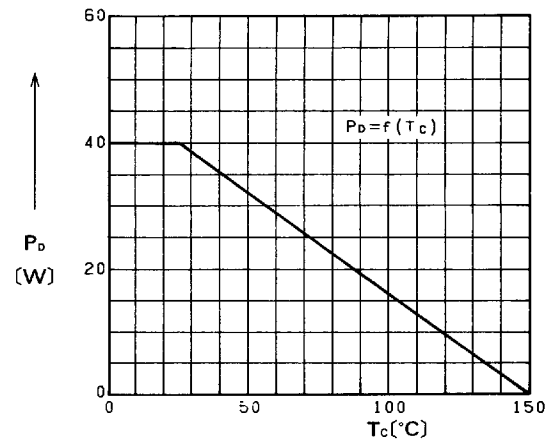
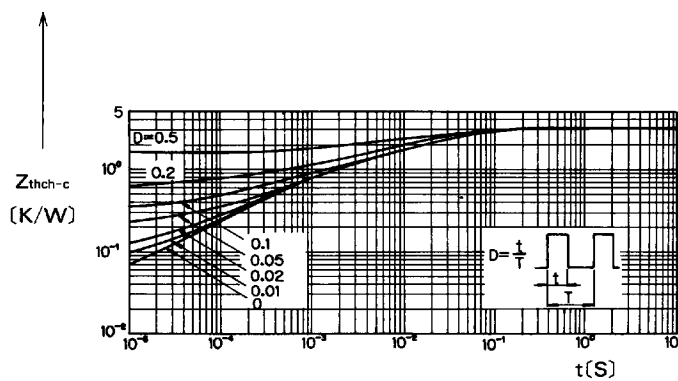
Typical Drain-Source On-State Resistance vs. I_D Typical Forward Transconductance vs. I_D Gate Threshold Voltage vs. T_{ch}

Typical Capacitance vs. V_{bs} 

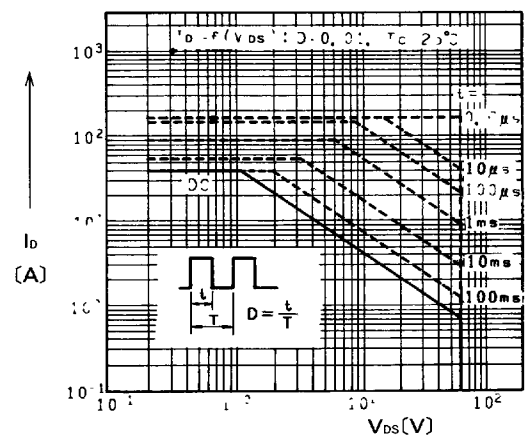
Typical Input Charge



Forward Characteristics of Reverse Diode

Allowable Power Dissipation vs. T_c 

Transient Thermal Impedance



Safe Operating Area